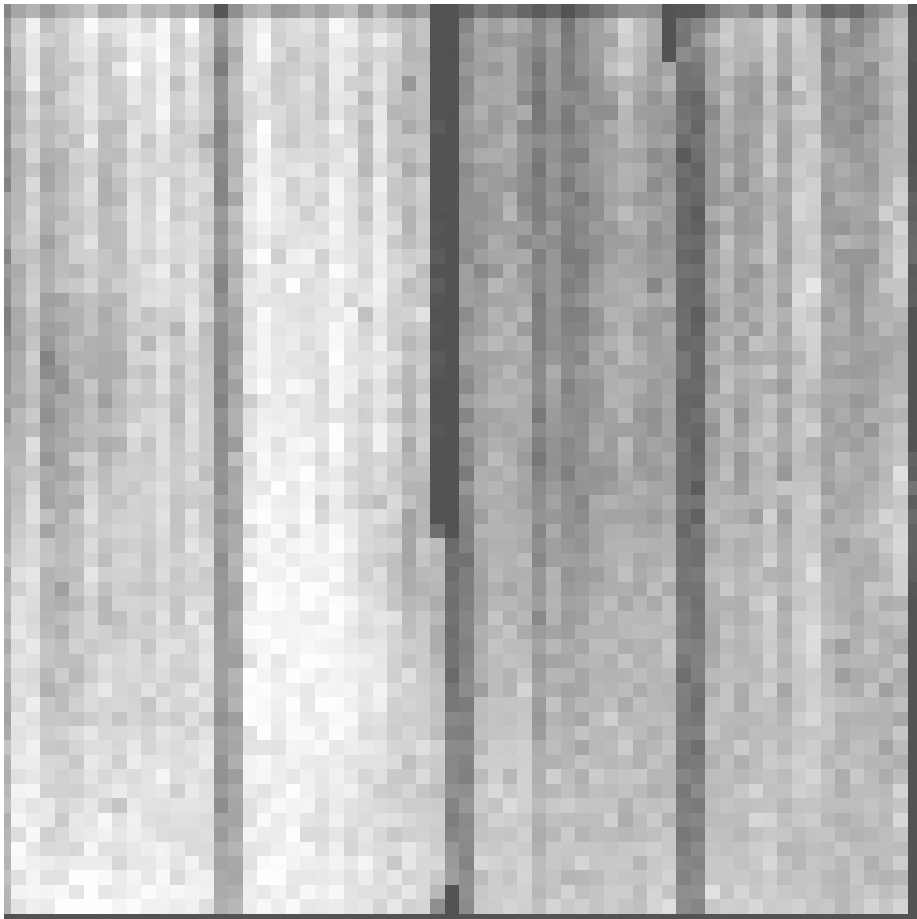
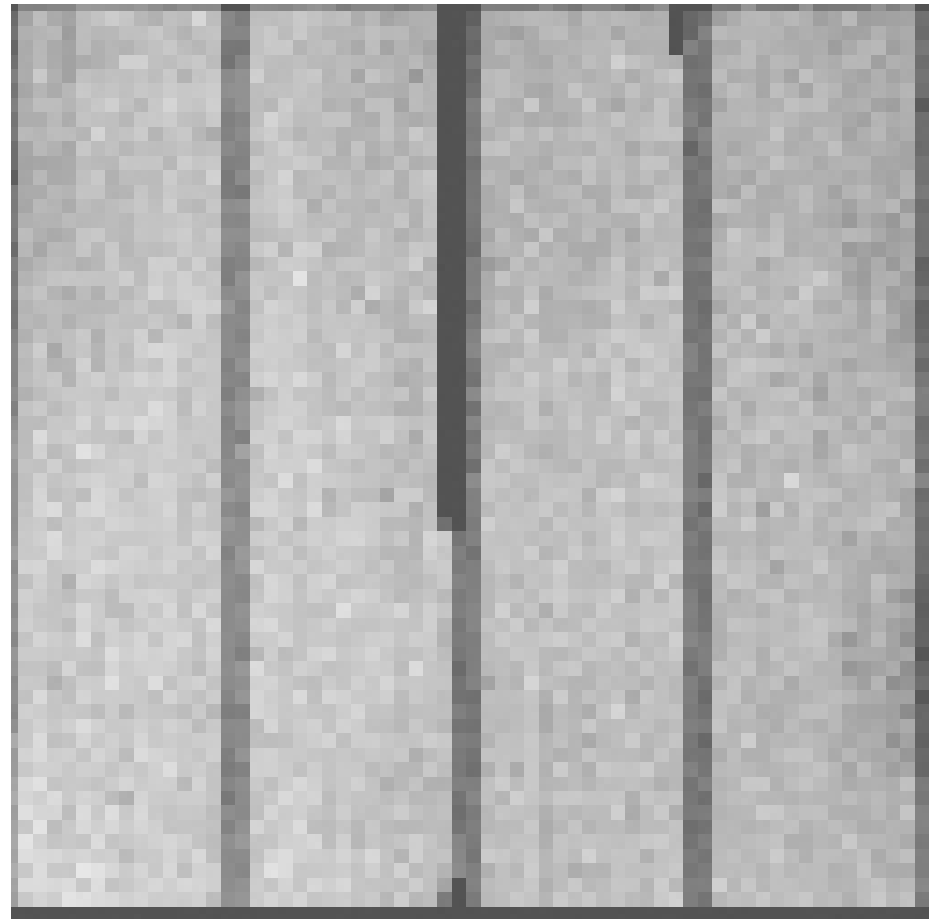


# HIGH-RESOLUTION ACIS QEU MAPS:

Improve QEU(CTI) from 7%



to 1% residuals

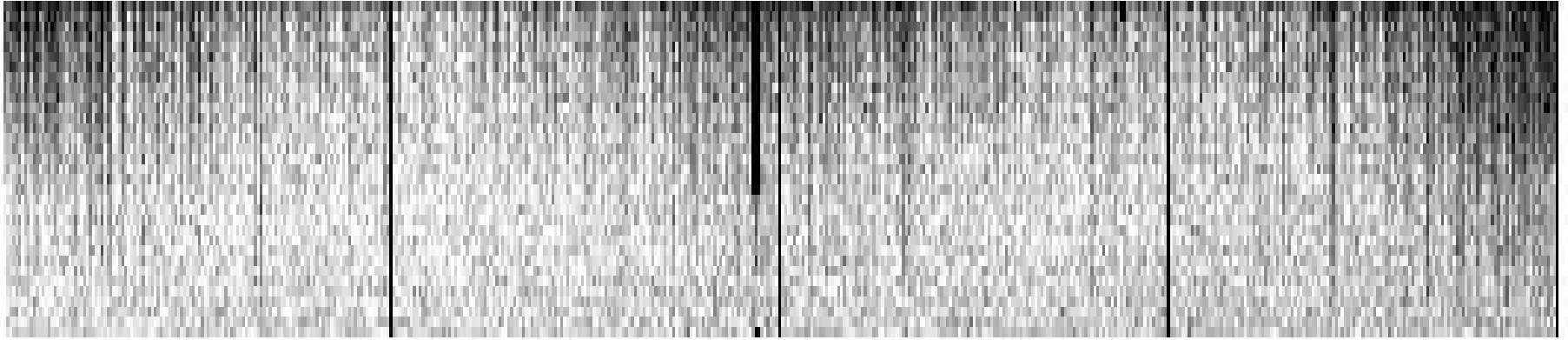


# HISTORY

- **Previous QEU calibration was derived from ground data and in-flight ECS exposures over  $\approx 1 - 2$  months.**
- **4 years worth of ECS measurements accumulated by 2004 revealed deficiencies:**
  - **5–7% residuals (both FI and BI)**
  - **strong column-to-column variations in the BI chips.**

# S3, Mn-Ka (5.9 keV)

chipy x 6



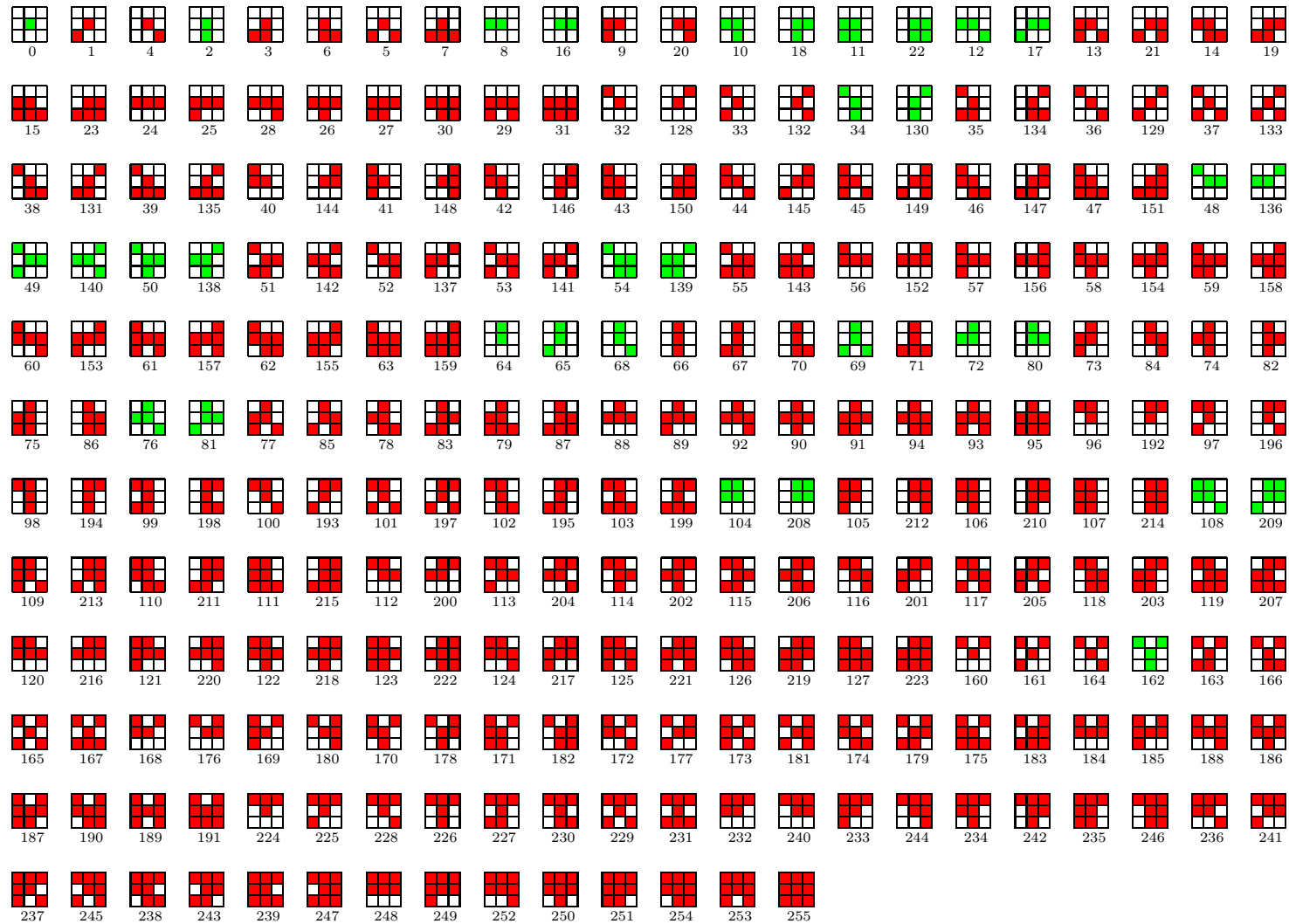
chipx

# HOW TO MEASURE QEU FROM FLIGHT DATA?

- $QEU(E_i) = \frac{\text{flux after CTI}}{\text{flux before CTI}} = \frac{\text{cnt}(Y, E_i)/\text{Illum}(Y, E_i)}{\text{cnt}(0, E_i)/\text{Illum}(0, E_i)}$
- $\text{Illum}(X, Y, E_i)$  can be derived from the ground ECS dataset because FI CCDs were “flat”
- **Problems:**
  - Flight data available only for  $E_i = 5.9, 4.5, 1.5$  keV
    - **how to determine  $QEU(E)$ ?**
  - Effects are small: 15–20% at 6 keV,  $\lesssim 5\%$  at 1.5 keV
    - **accurate measurements are hard**
- Linear interpolation/extrapolation over  $E$  was used before; accuracy insufficient for 1% calibration.

# HOW TO ENHANCE QEU?

- CTI effect on QE is due to grade migration
- We need to enhance the QEU “signal”. *Idea:*  
**Only a subset of ACIS flight grades can migrate into bad grades**



**0, 8, 16, 64, 72, 80, 104, 208 migrate into each other**

— “Good” good set (GG)

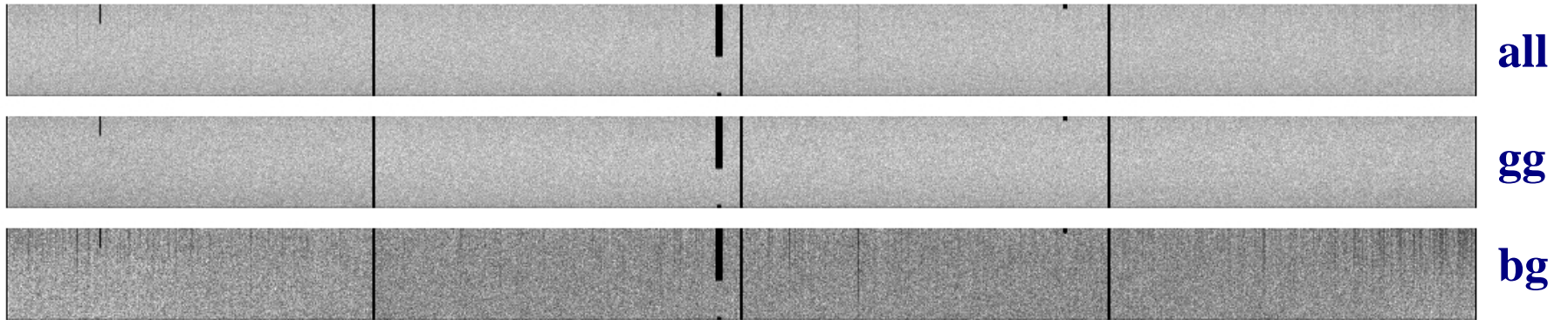
**2, 10, 18, 11, 22 migrate into bad grades**

— “Bad” good set (BG)

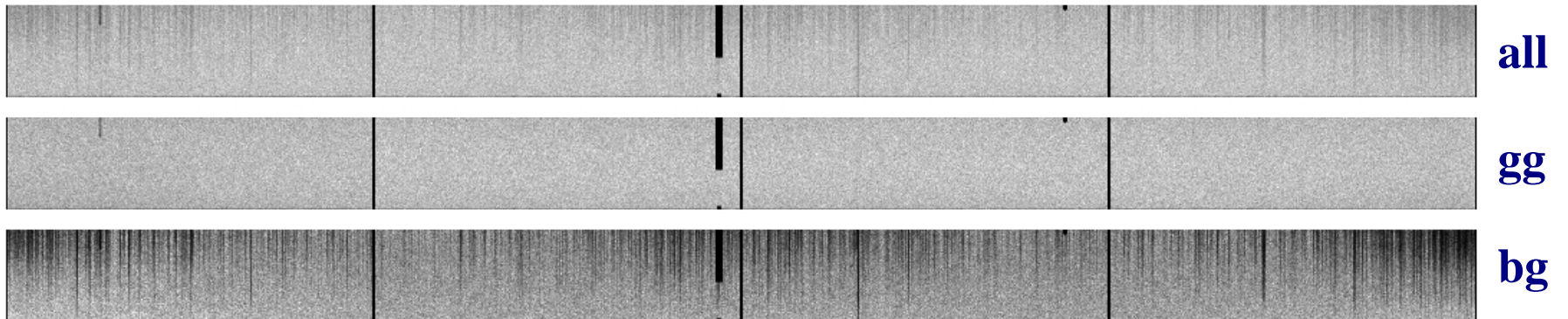
**Prediction: QEU is strong for BG, absent for GG**

# ACIS-S3

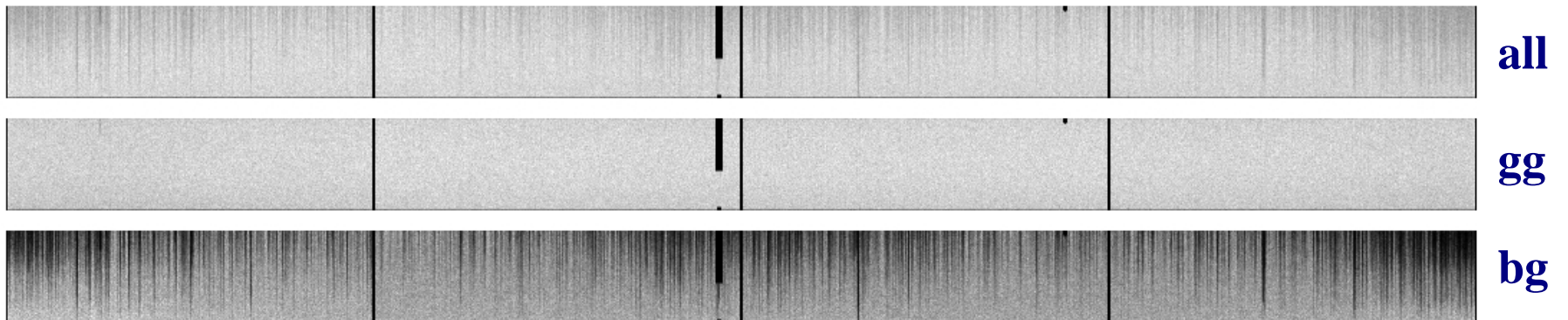
**1.5 keV:**



**4.5 keV:**



**5.9 keV:**

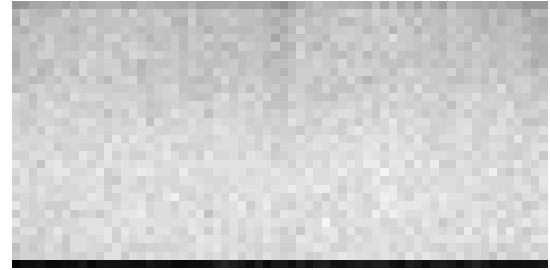
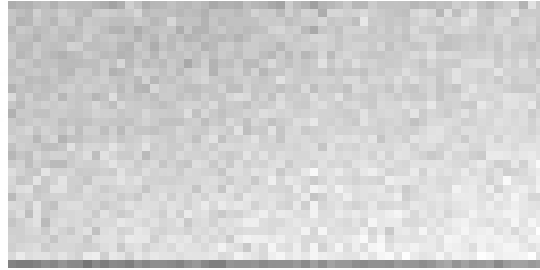
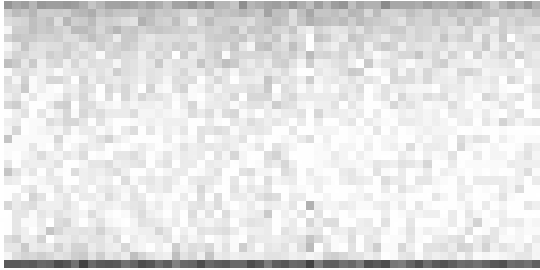


# ACIS-S2

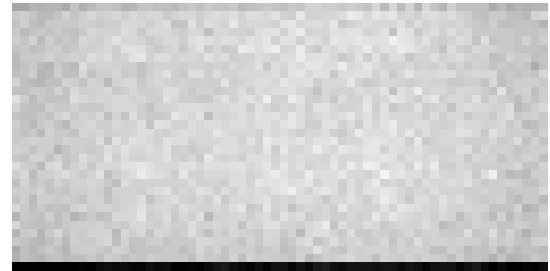
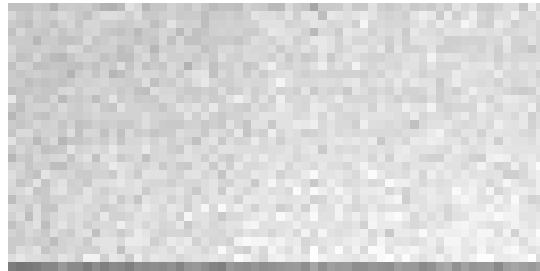
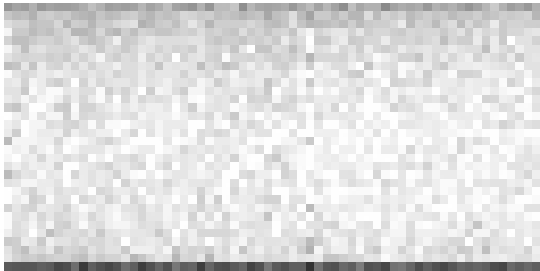
**1.5 keV**

**4.5 keV**

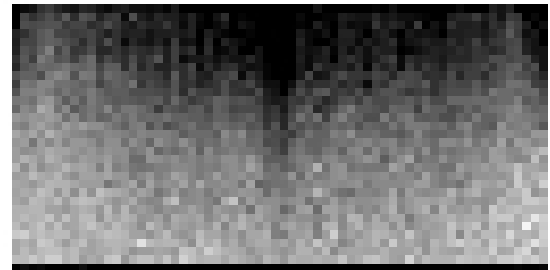
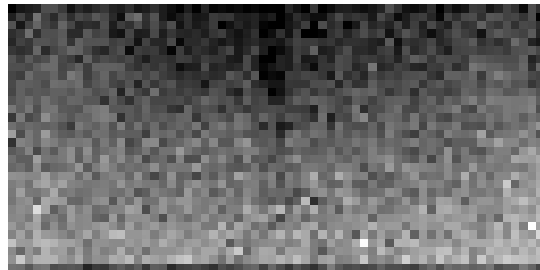
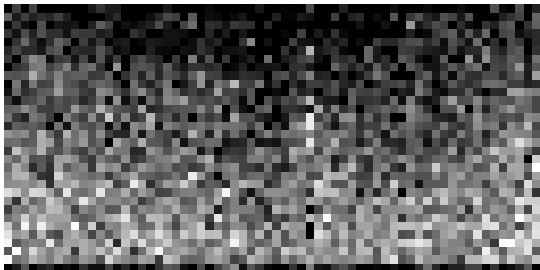
**5.9 keV**



**All**



**GG**



**BG**

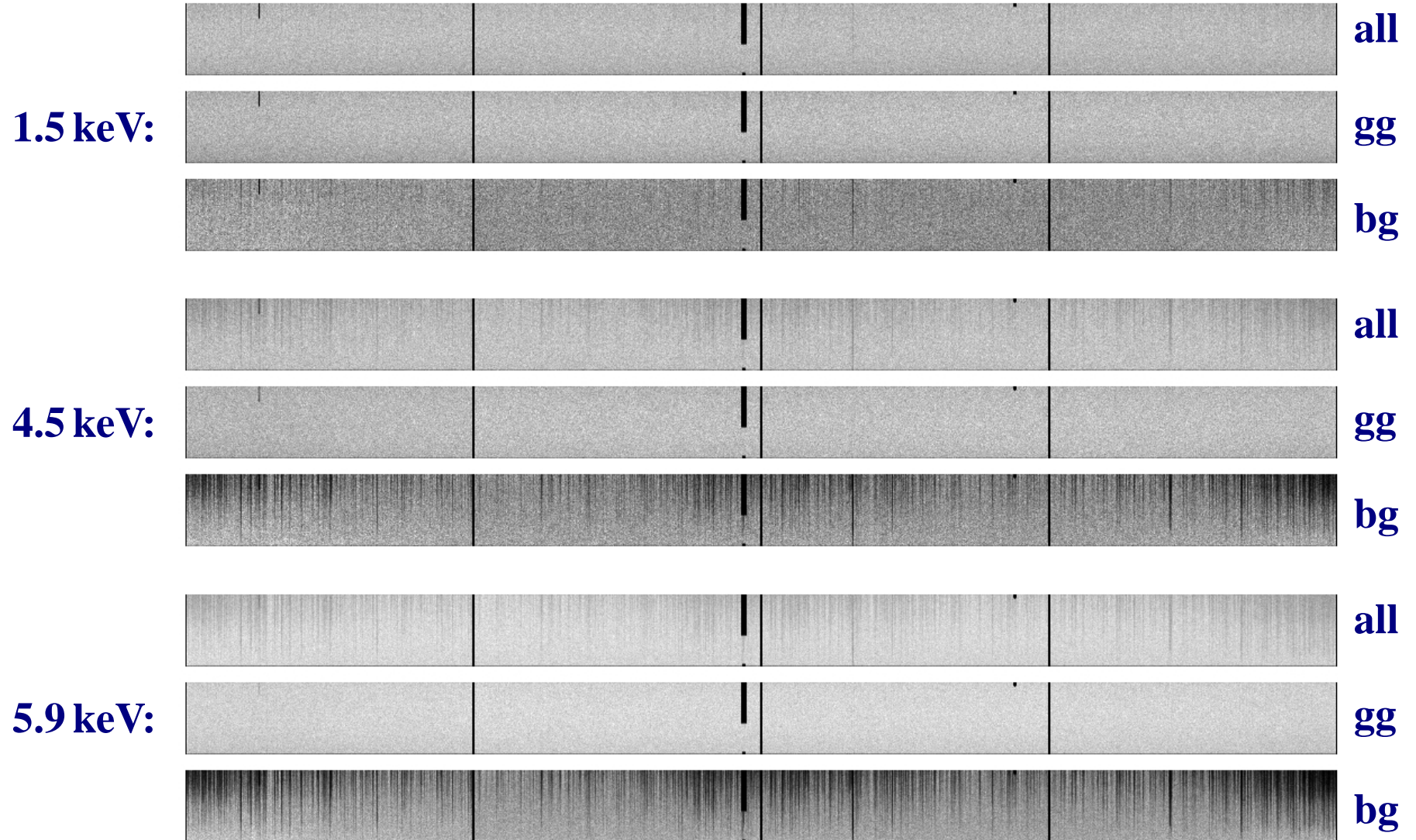


## PLAN:

1. Derive QEU for BG set,  $QEU_{BG}(X, Y, E)$ ,
2. derive fractional flux in BG set,  $f_{BG}(E)$ ,
3. and then

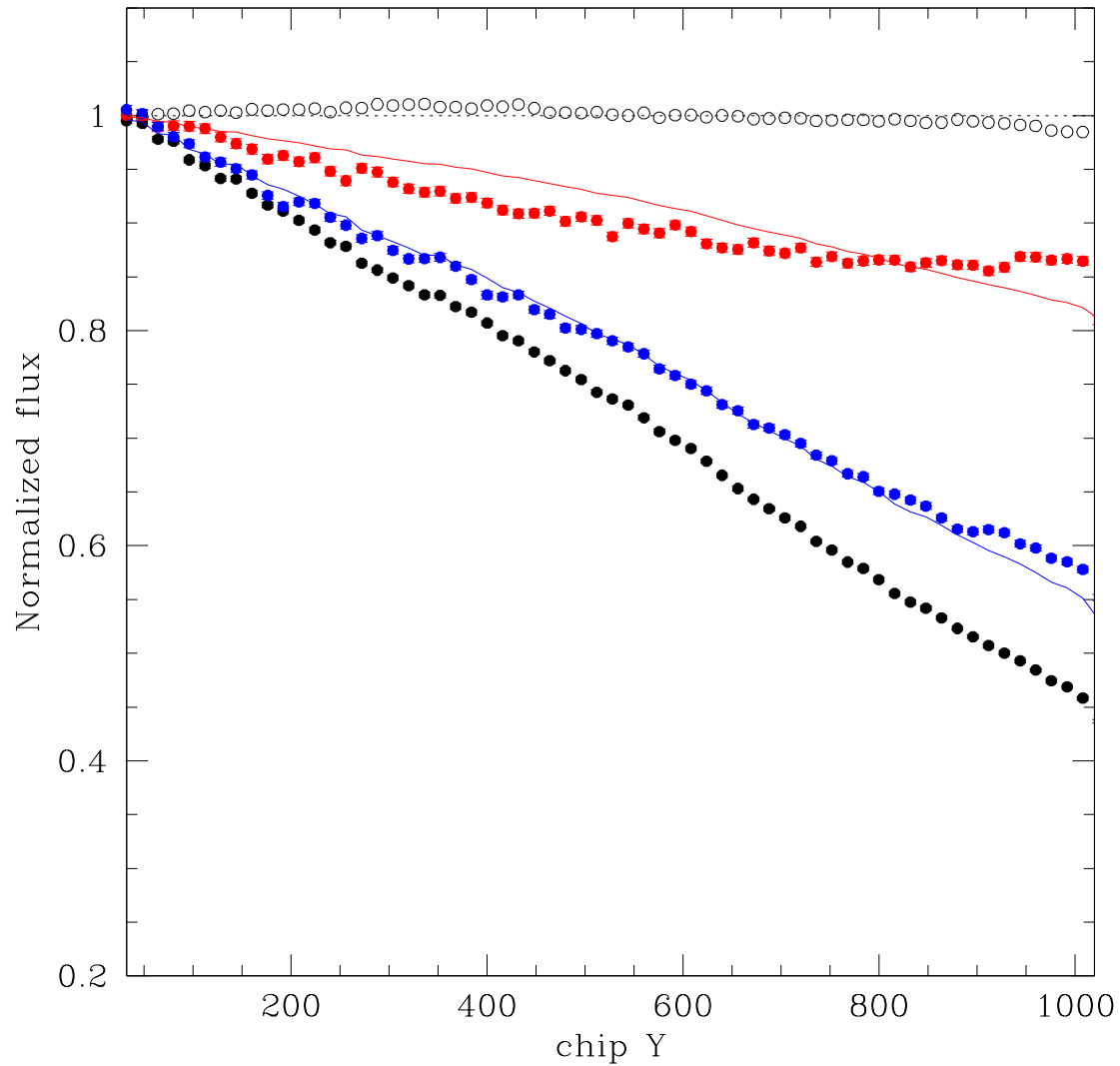
$$QEU(X, Y, E) = 1 + f_{BG}(E) \times (QEU_{BG}(X, Y, E) - 1)$$

# QEU(E) for BG



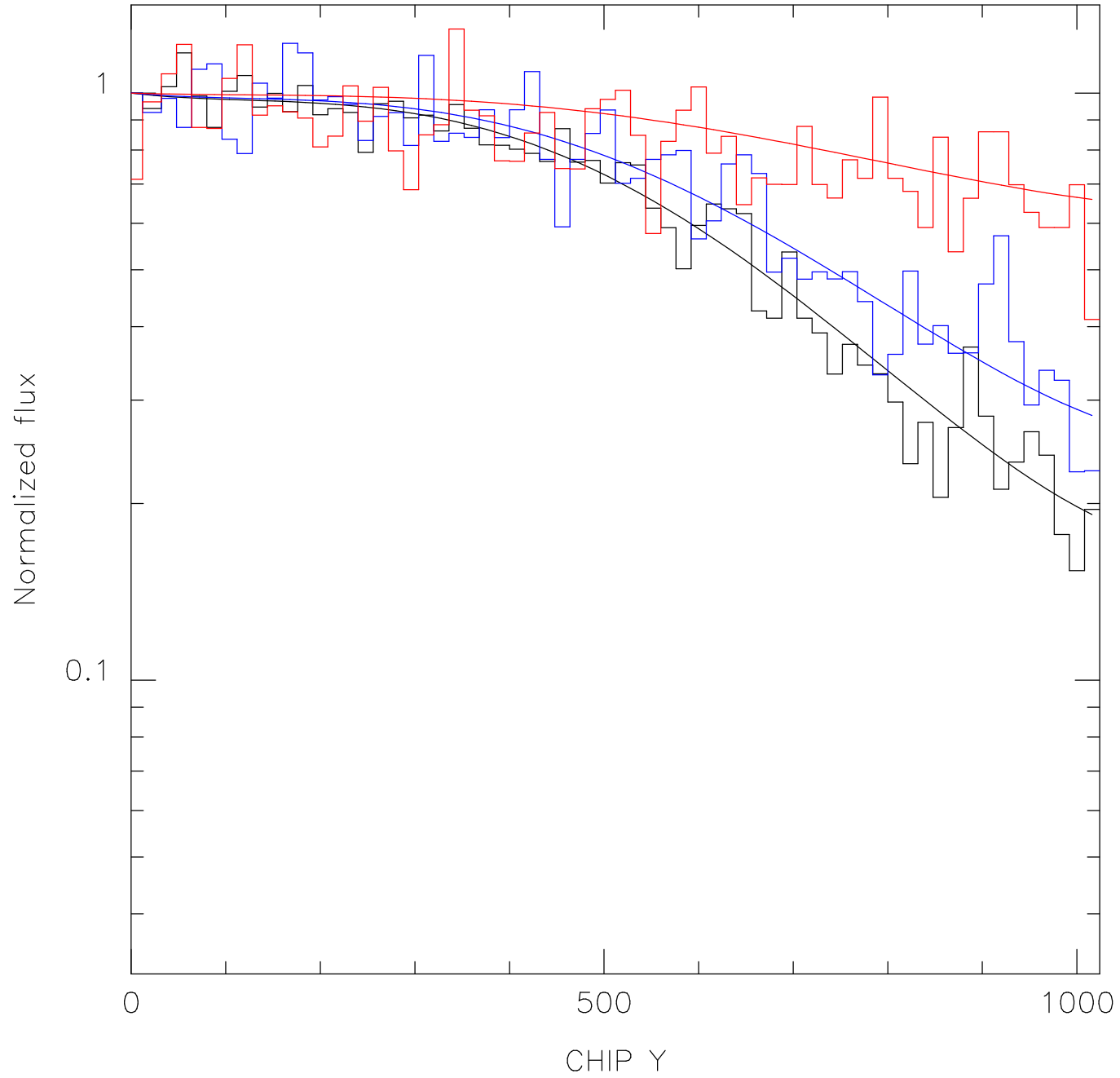
$$\text{QEU}_{\text{BG}}(X, Y, E) = f(X, Y) \times g(E)$$

# QEU(E) for BG

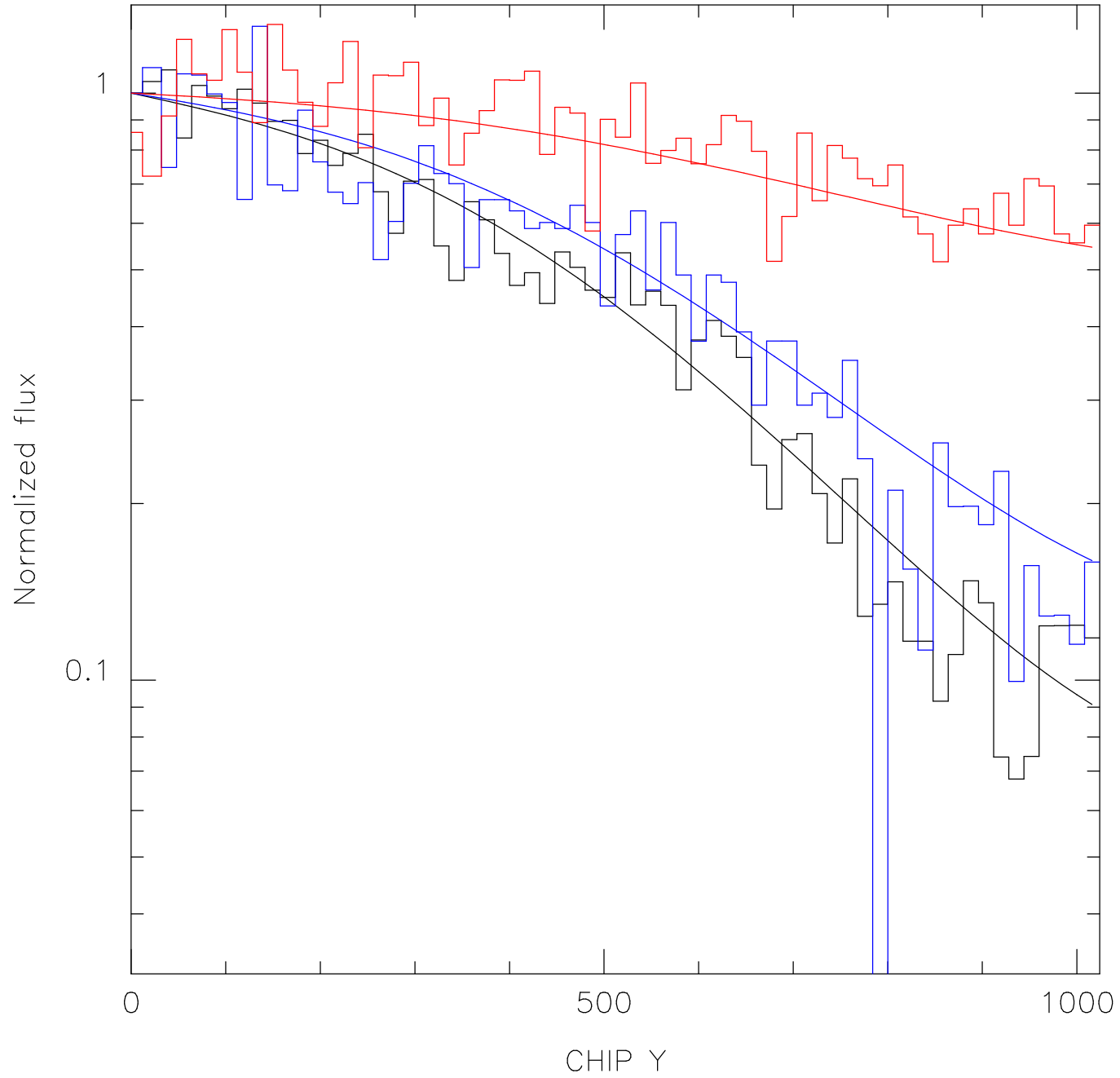


- flux loss  $\propto \log E$  — verified at 0.5, 0.7, 1.7, 2.2, 6.4, 8.0 keV (XRCF)
- spatial dependence can be derived using the brightest line, Mn-K

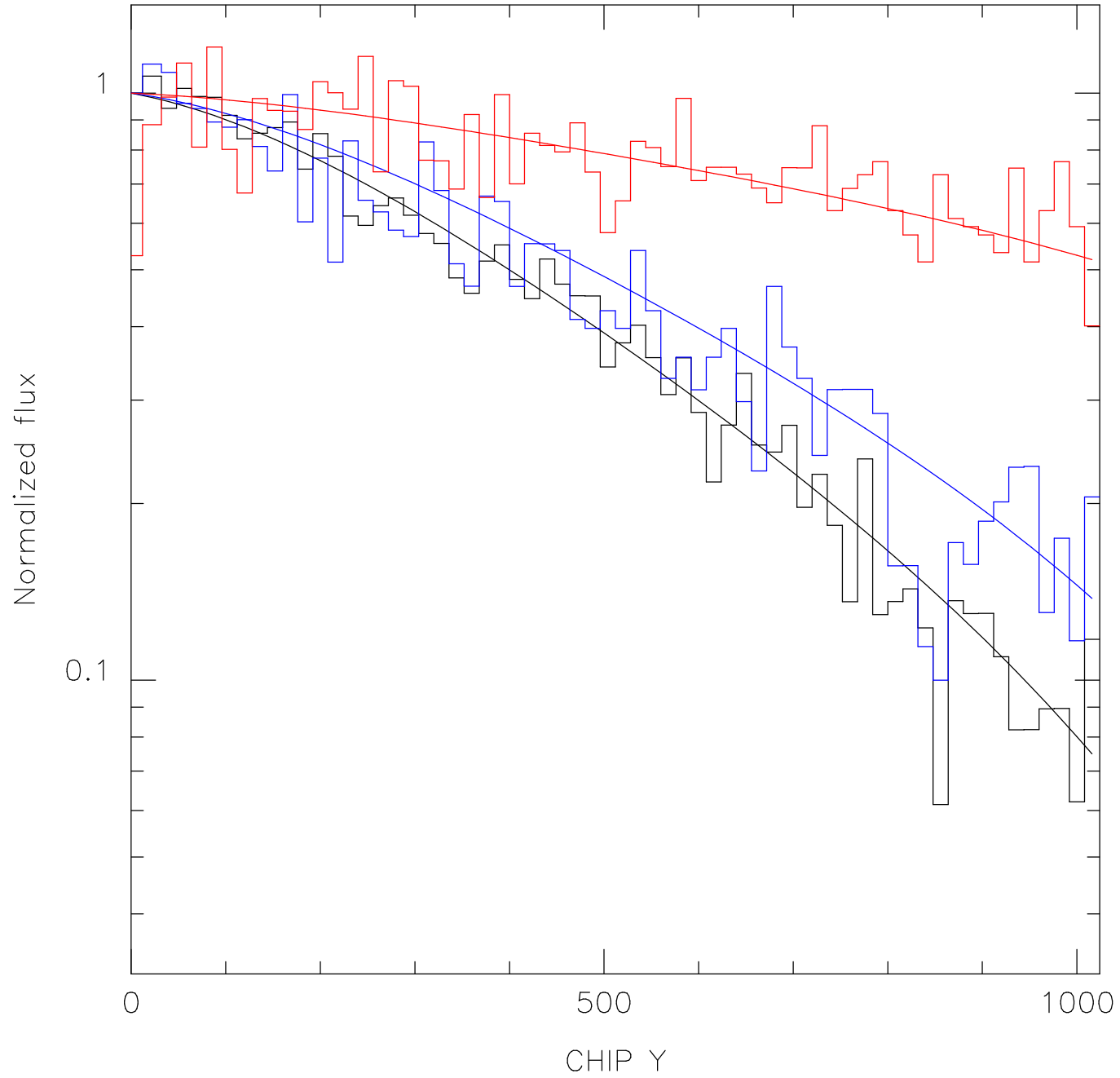
# QEU(X,Y) for BG



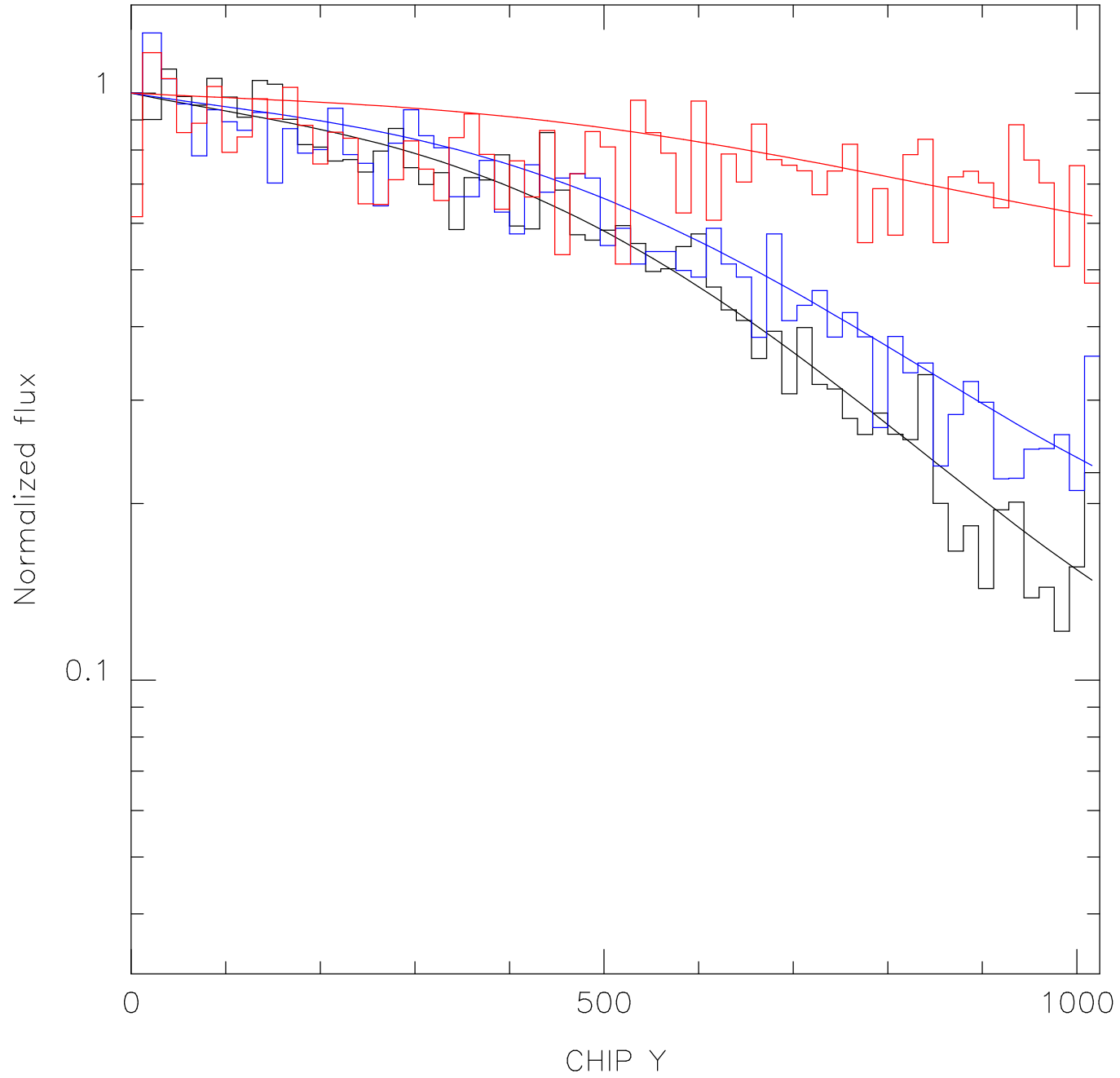
# QEU(X,Y) for BG



# QEU(X,Y) for BG



# QEU(X,Y) for BG

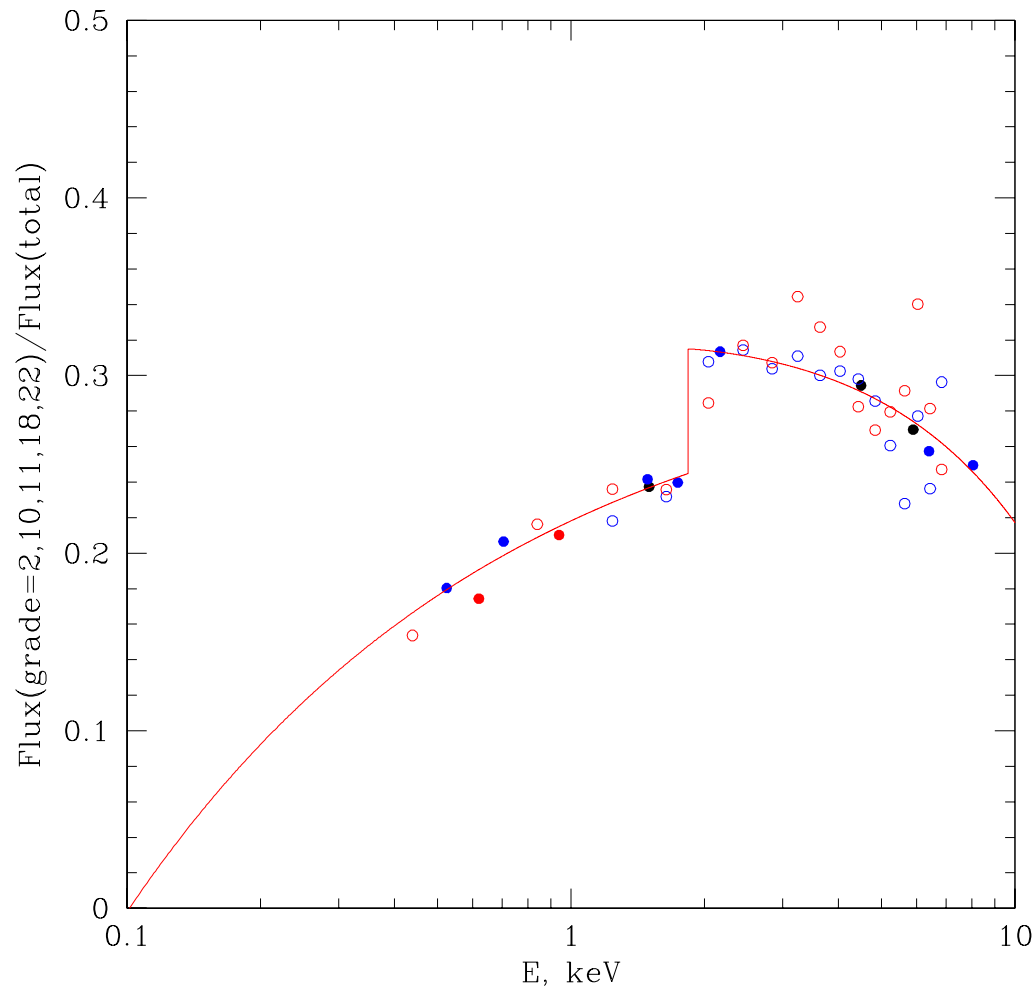


# QEU(X,Y) for BG

- Correction ( $Y$ ) measured in *each column* from Mn-K  
— strong effect, high flux  $\implies$  accurate measurement
- Correction ( $X, Y, E$ ) = Correction ( $X, Y, \text{Mn}$ )  $\times \frac{\log E}{\log 5.9}$
- Last step: derive  $f_{\text{BG}}(E)$

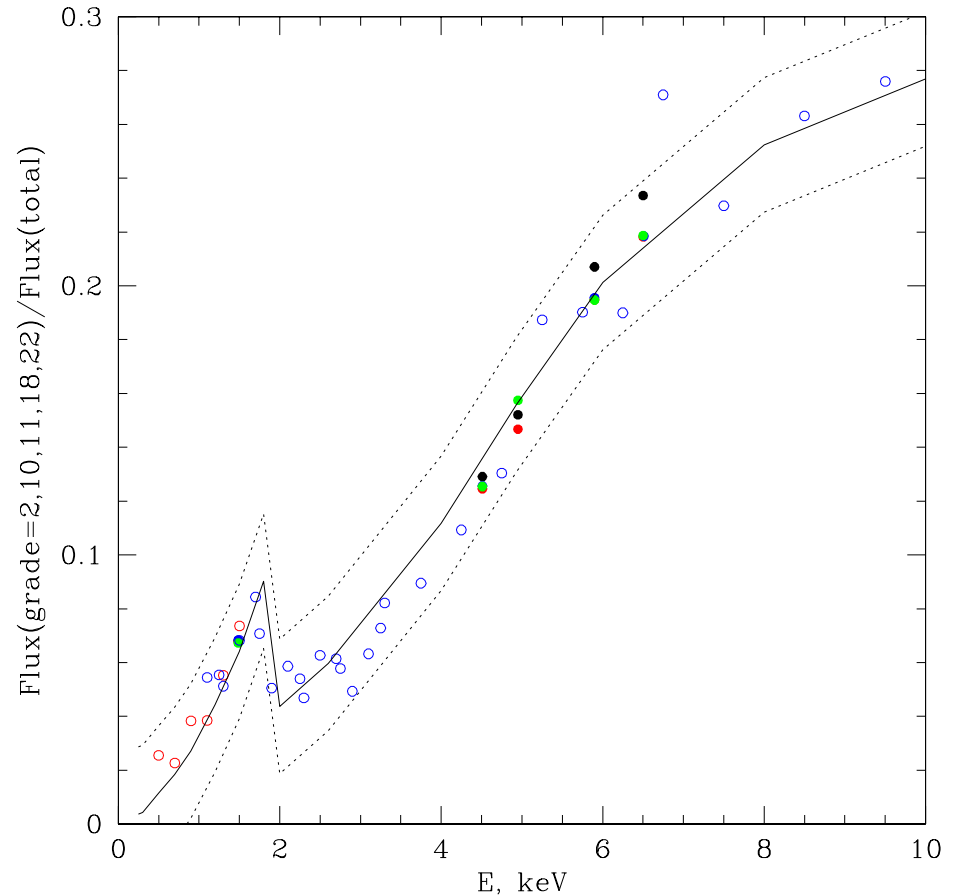
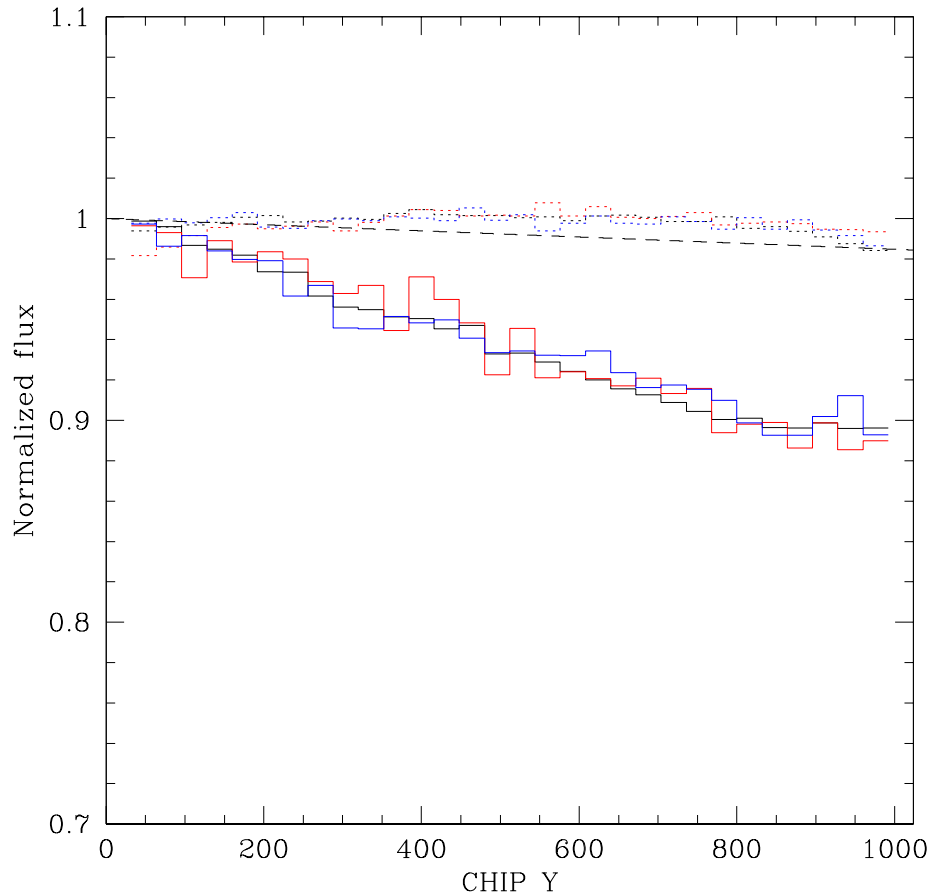


$f_{\text{BG}}(E)$



- $f_{\text{BG}}(E)$  can be measured accurately from calibration data: **ECS**, **XRCF**, **E0102**
- ... less accurately with **G21.5** and **A1795** at intermediate energies
- Jump between 1918 and 2004 eV
- Empirical fit:
  - $f(E) = 0.32 \times (1 - 0.45 (0.5/E)^{0.5})$  for  $E < 1.837$  keV
  - $f(E) = 0.315 \times (1 - 0.0225 (E - 1.837)^{1.25})$  for  $E > 1.837$  keV

# FI chips

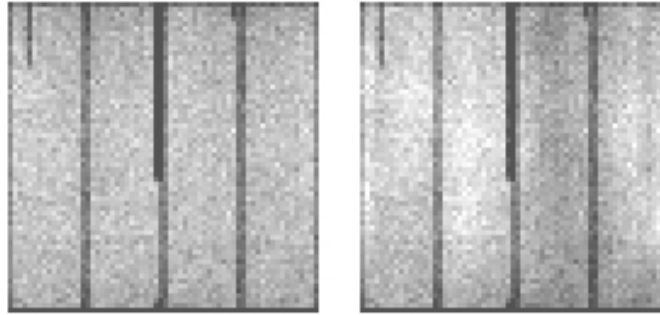


- **Identical procedure for FI chips**

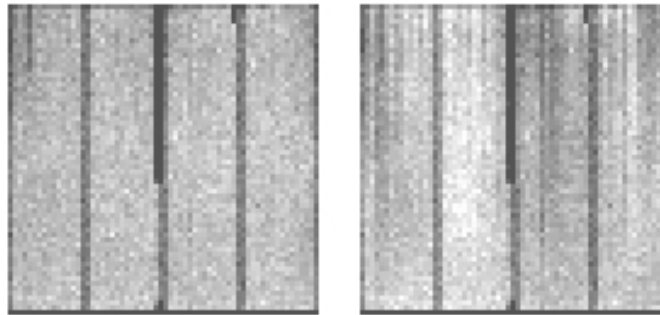
- **No detectable column-to-column variation, bin `chipx` by 4**
- **Correction in BG set independent of energy**
- **Different  $f_{BG}(E)$**

# Test: S3

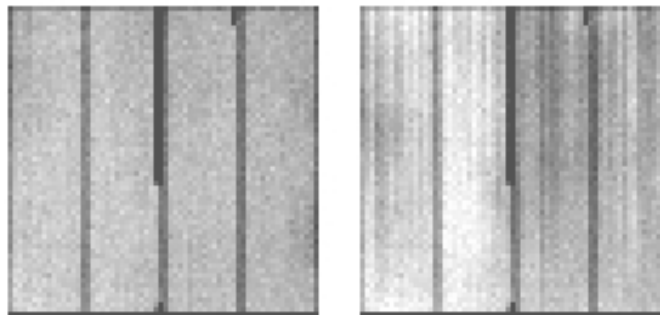
1.5 keV



4.5 keV



5.9 keV



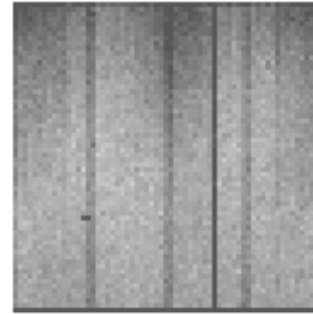
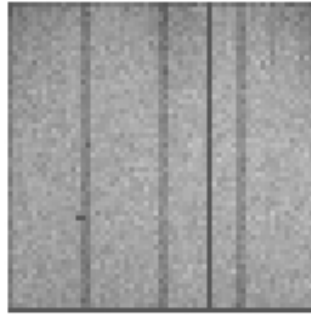
new

old

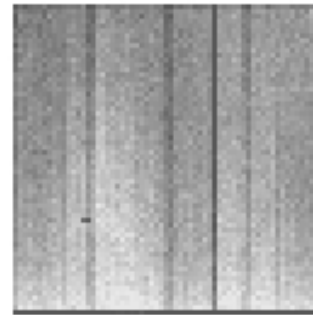
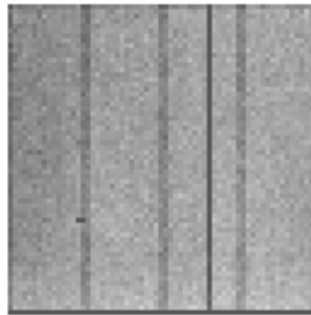
$\pm 7\%$  residuals (rms)  $\longrightarrow$   $\pm 1\%$  (rms),  $\pm 3\%$  (max)

# Test: S1

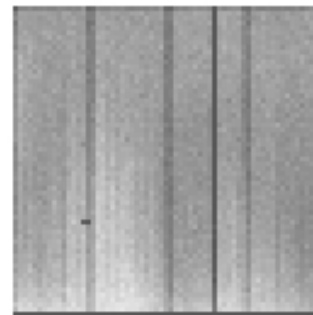
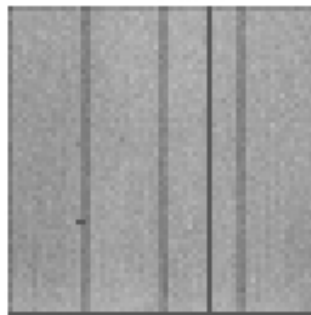
1.5 keV



4.5 keV



5.9 keV

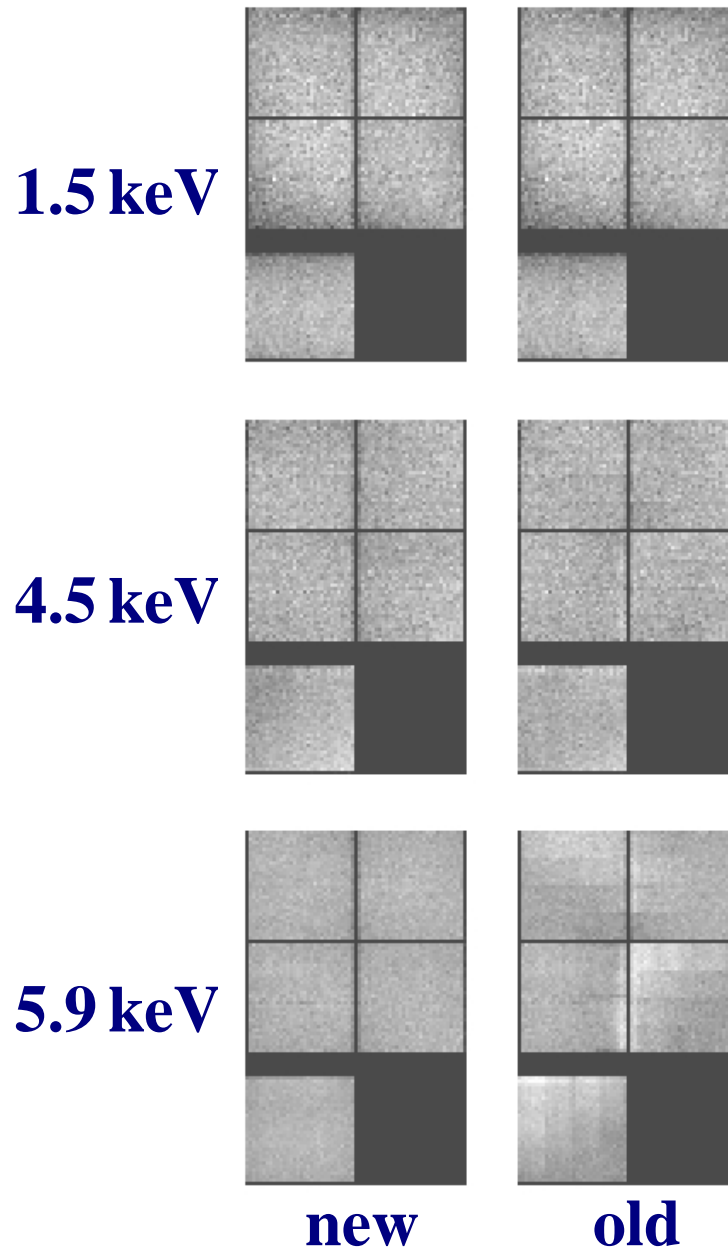


new

old

$\pm 10\%$  residuals (rms)  $\longrightarrow$   $\pm 3\%$  (rms, max),

# Test: FI chips



+7%, -3% at high energies →  $< \pm 1\%$  (rms),  $< \pm 2\%$  (max)